

allow high array density and support lower operating voltages, which makes them ideal for battery-less energy harvesting systems. As shown in Fig. 2, emerging nonvolatile memory technologies have considerable potential in further expanding read and write bandwidth [7]-[33], [44]-[45].

3. Computing in Memory (CIM)

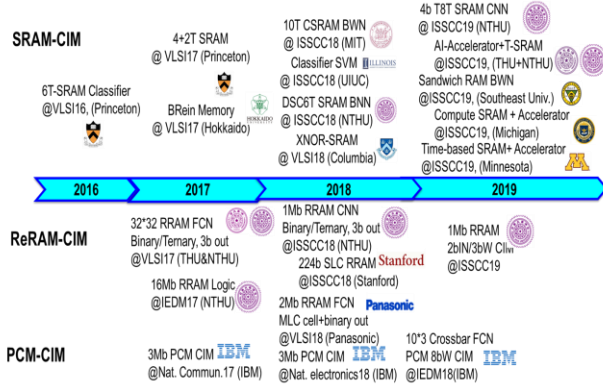


Fig. 3. Roadmap of the development of CIM structures

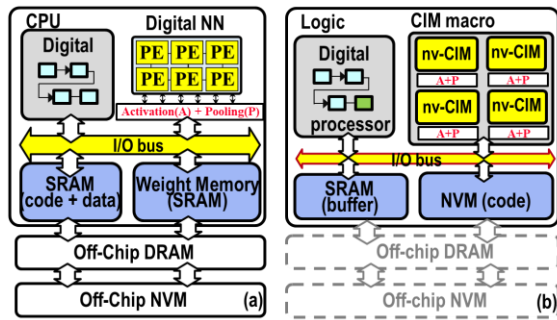


Fig. 4. Comparison of (a) conventional von Neumann and (b) CIM architectures

Deep neural networks (DNNs) [1]-[4] require the movement of large amounts of data between memory devices and the CPU. Multiply and accumulate (MAC) operations dominate the computational workload in convolutional neural networks (CNN) and fully connected neural networks (FC). The computing in memory (CIM) structure was developed to overcome the memory wall in the development of DNN processors for AI edge devices, with the aim reducing power consumption, increasing inference speeds, and enhancing energy efficiency [34]-[35]. Fig. 3 presents a roadmap showing recent developments in the CIM structure.

3.1 Concept of CIM

Computing-in-memory (CIM) overcomes the von-Neumann bottleneck by performing computational processing directly within the memory macros. This enables highly parallel computation, suppresses the

amount of intermediate data, and allows the completion of MAC operations within fewer cycles. Fig. 4 presents block diagrams of the conventional von-Neumann and CIM architectures. Numerous silicon proven CIMs have also been developed using SRAM (SRAM-CIM) and NVM (nvCIM); however, they impose a different set of circuit design challenges.

3.2 Circuit Design Challenges of SRAM-CIM

Recent advances in SRAM-CIM include a 6T SRAM-based error adaptive classifier for MNIST recognition [38], a dual-wordline-control 6T SRAM-based SRAM-CIM macro for fully connected layers [20], a 10T Conv-SRAM for binary weight neural networks [37], a deep-in-memory machine learning classifier with on-chip training [43], and a twin-8T SRAM-CIM for multi-bit neural networks [41]. This research has clearly demonstrated the benefits of the CIM architecture in terms of functionality and energy efficiency.

Multibit CNNs are required to improve the inference accuracy of machine learning applications under the increased data complexity following the shift from the MNIST to Image-Net datasets [1]-[6]. Researchers face several challenges and tradeoffs in the design of multi-bit SRAM-CIM: (a) write disturb when performing MAC operations, (b) limited signal margin with an increase in the number of MAC operations, (c) excessive area overhead in signed weight implementation, and (d) large area overhead and power consumption in generating reference signals for multi-bit readouts.

Several solutions have been proposed to overcome these issues, including the use of larger SRAM bit cells (e.g., twin-8T [41] and 10T SRAM cell [37]), the development of small offset sense amplifiers [20], and efficient mapping methods for the CIM structure (e.g., two's complement weight mapping [41]).

3.2 Circuit Design Challenges of nvCIM

Recent developments in CIM architectures based on emerging nonvolatile memory (NVM) devices, such as resistive RAM (ReRAM) [35],[40], and phase change memory (PCM), have greatly improved processing speeds and energy efficiency. The high resistance ratio and ease of mass manufacturing in foundries have made 1T1R single-level-cell (SLC) ReRAM a prime candidate for nonvolatile CIM (nvCIM). Previous ReRAM CIM macros have been used for MAC operations, including binary-input ternary-weight with 3-bit outputs for the MNIST dataset [35], binary-input 8-bit weights with binary-outputs for fully-connected networks, and 2-bit input 3-bit weights with 4-bit outputs for the CIFAR-10 dataset [42].

However, designing circuits for SLC ReRAM-based nvCIM for multi-bit MAC operations imposes a number

of challenges: (a) a tradeoff between area cost, speed, and power consumption in the placement of multi-bit inputs and weights within the memory cell array, (b) high input offset, and large parasitic load on the read-path, due to high maximum bitline (BL) current (I_{BL}) across MAC values (MACs), and (c) limited inference accuracy induced by small read margin across various input-weights patterns and variations in memory cell resistance.

4. Summary

Rapid developments in IoT and AI technologies have exposed several fundamental challenges inherent to the von Neumann computing architecture. This article explores recent trends in volatile (SRAM) and nonvolatile memory (including PCM, STT-MRAM, and ReRAM). We also look at recent developments and the challenges ahead in the development of SRAM and nonvolatile memory (NVM)-based CIM structures, the objective of which is to reduce the amount of data that must be moved between processors and memory.

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